Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination	
10660796	NAGAO, SEIJI	
Examiner	Art Unit	
Carter, Aaron W	2624	

SEARCHED					
Class	Subclass	Date	Examiner		
382	141-152	12/19/06	AWC		
348	125-134, 86-112	12/19/06	AWC		
356	237.1-237.6	12/19/06	AWC		
705	4	12/19/06	AWC		

SEARCH NOTES				
Search Notes	Date	Examiner		
EAST Text Search (USPAT, PGPUB) See Search History Printout	12/19/06	AWC		
Inventor Name Search (See PALM Search History Printout, Check Marks Indicate Applications Considered)	12/19/06	AWC		
IEEE Search (See Search History Printout)	12/19/06	AWC		

INTERFERENCE SEARCH				
Class	Subclass	Date	Examine	

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